Electronic Supplementary Material (ESI) for RSC Advances.

supplementary information

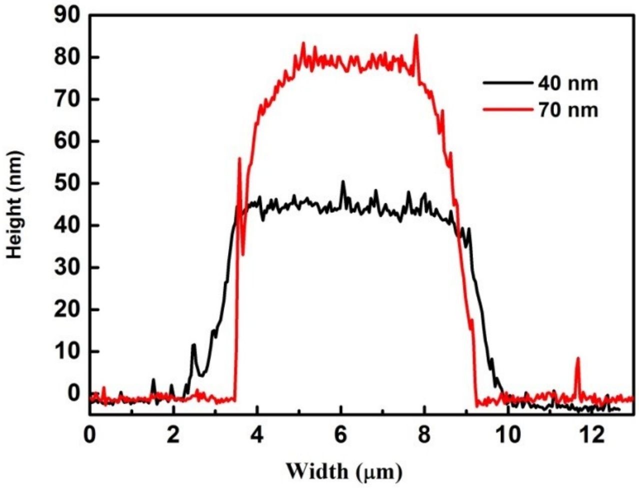

Fig. S1 the AFM profile of the Ag mesh films with the thickness of 40 nm and 70 nm, respectively.

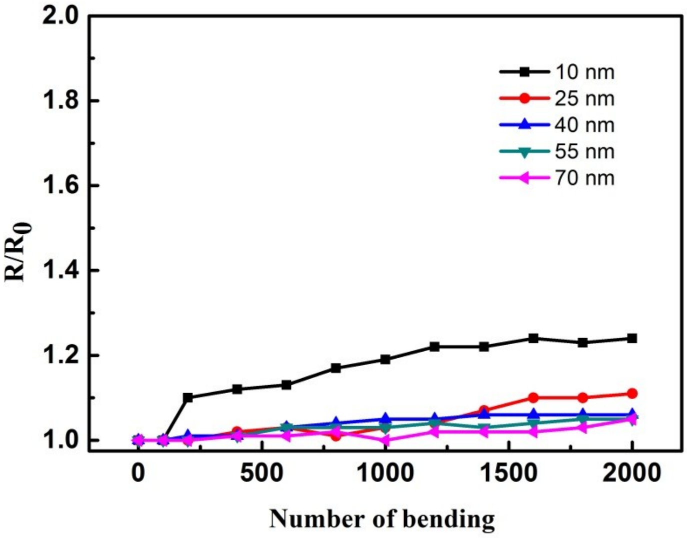

Fig. S2 the change of resistance of Ag mesh films with different thickness after repeated bending test.

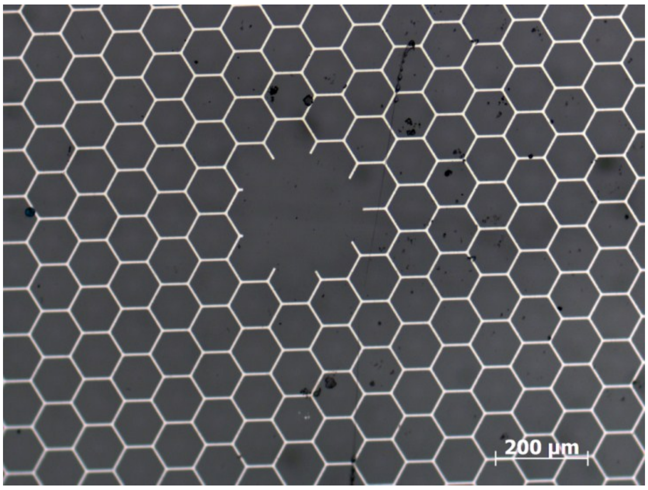

Fig. S3 the image of the 70 nm Ag mesh film after 100 cycles tape test observed using confocal laser scanning microscope.